

HVV1011-075L

75 Watts, 50V, 1200-1400MHz 32uS on/18uS off x 48, repeated every 24ms

DESCRIPTION

The high power HVV1011-075L device is a high voltage silicon enhancement mode RF transistor designed for L-band pulsed applications operating at 1030 and 1090 MHz using a 2.4ms pulse burst (32 μ s on/18 μ s off x 48) repeated every 24ms.

FEATURES

High Power Gain Excellent Ruggedness 50V Supply Voltage

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter Value		Unit
V _{DSS}	Drain-Source Voltage	n-Source Voltage 95	
V _{GS}	Gate-Source Voltage -10 to		V
		10	
I _{DSX}	Drain Current	8	A
P_D^2	Power Dissipation	625	W
Ts	Storage Temperature		°C
		+150	
Tj	Junction		°C
	Temperature		

THERMAL CHARACTERISTICS

Symbol	Parameter	Max	Unit
θ_{JC}^{1}	Thermal Resistance	0.28	°C/W

ELECTRICAL CHARACTERISTICS



The device utilizes a RoHS compliant metal ceramic flanged package with a ceramic lid. The HV400A package style is qualified for gross leak test – MIL-STD-883, Method 1014.

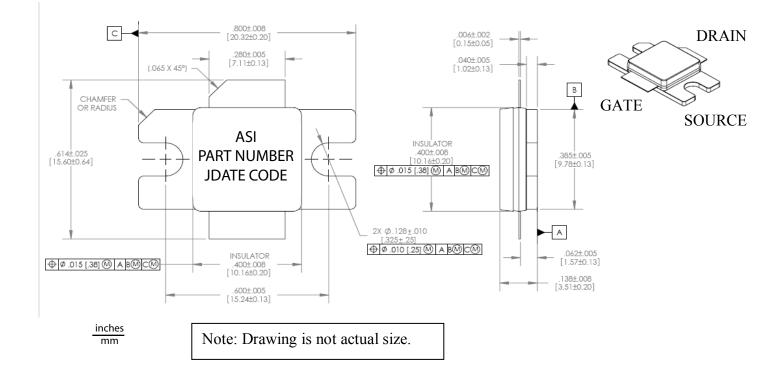
RUGGEDNESS

The HVV1011-075L device is capable of withstanding an output load mismatch corresponding to a 20:1 VSWR at rated output power over all phase angles and operating voltage across the frequency band of operation.

Symbol	Parameter	Test Condition	Max	Units
LMT^1	Load	P _{OUT} = 75W	20:1	VSWR
	Mismatch Tolerance	F = 1030 MHz		

Parameter	Conditions	Тур	Units
Drain-Source Breakdown	$V_{GS}=0V, I_{D}=2mA$	102	V
Drain Leakage Current	$V_{GS}=0V, V_{DS}=50V$	<100	μA
Gate Leakage Current	$V_{GS}=5V, V_{DS}=0V$	<1	μA
Power Gain	P _{in} =0.75W, F=1030/1090 MHz	20.5	dB
Input Return Loss	P _{in} =0.75W, F=1030/1090 MHz	12	dB
Power Out	P _{in} =0.75W, F=1030/1090 MHz	84	W
Drain Efficiency	P _{in} =0.75W, F=1030/1090 MHz	45%	%
-Burst Droop	$P_{in} = 0.75W, F = 1030/1090 MHz 30MA$	0.7	dB
	Drain-Source Breakdown Drain Leakage Current Gate Leakage Current Power Gain Input Return Loss	Drain-Source Breakdown $V_{GS}=0V$, $I_D=2mA$ Drain Leakage Current $V_{GS}=0V$, $V_{DS}=50V$ Gate Leakage Current $V_{GS}=5V$, $V_{DS}=0V$ Power Gain $P_{in}=0.75W$, $F=1030/1090$ MHzInput Return Loss $P_{in}=0.75W$, $F=1030/1090$ MHzDower Qut $P_{in}=0.75W$, $F=1030/1090$ MHz	Drain-Source Breakdown $V_{GS}=0V$, $I_D=2mA$ 102 Drain Leakage Current $V_{GS}=0V$, $V_{DS}=50V$ <100

REV. A



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